

Week 12

Light Detectors 2

Measuring solar cell efficiency

OPV Architectures, Morphologies and Materials

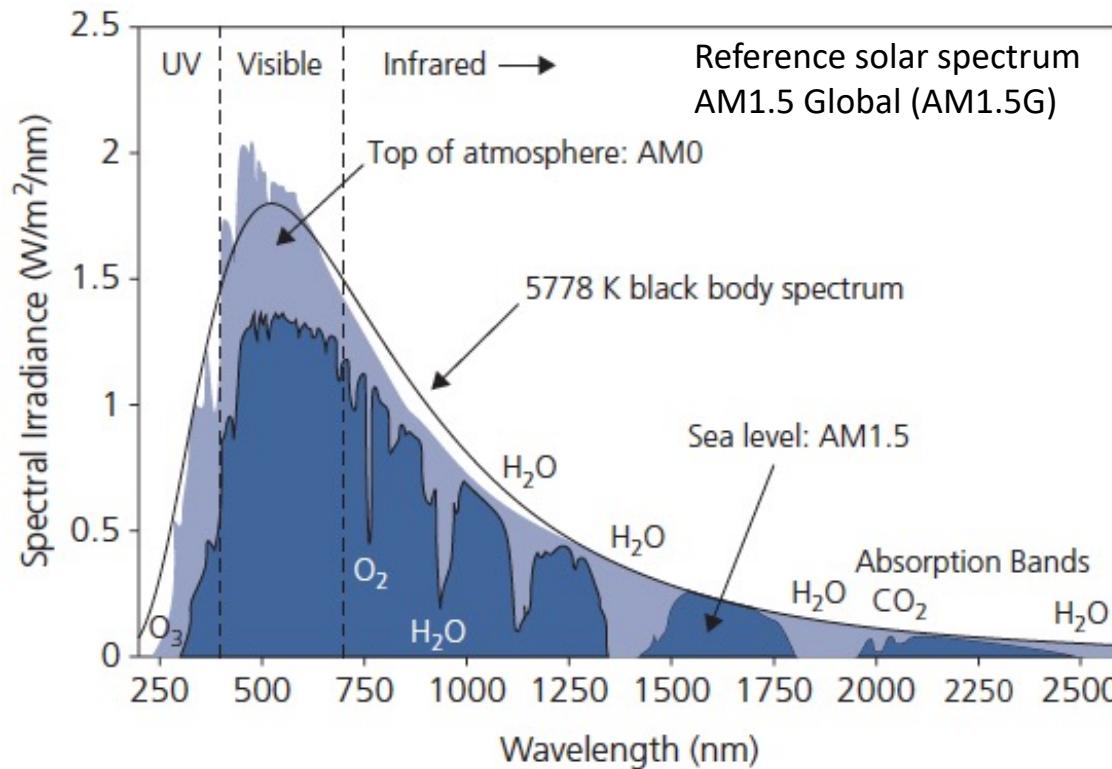
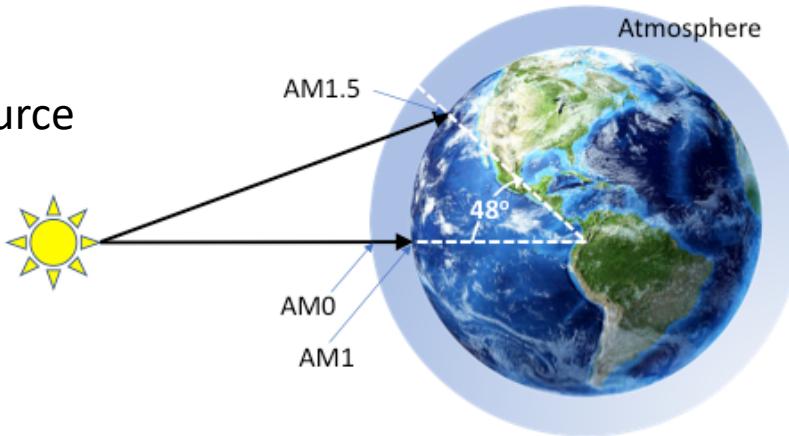
Transparency

Chapter 7.3.3-7.4.3

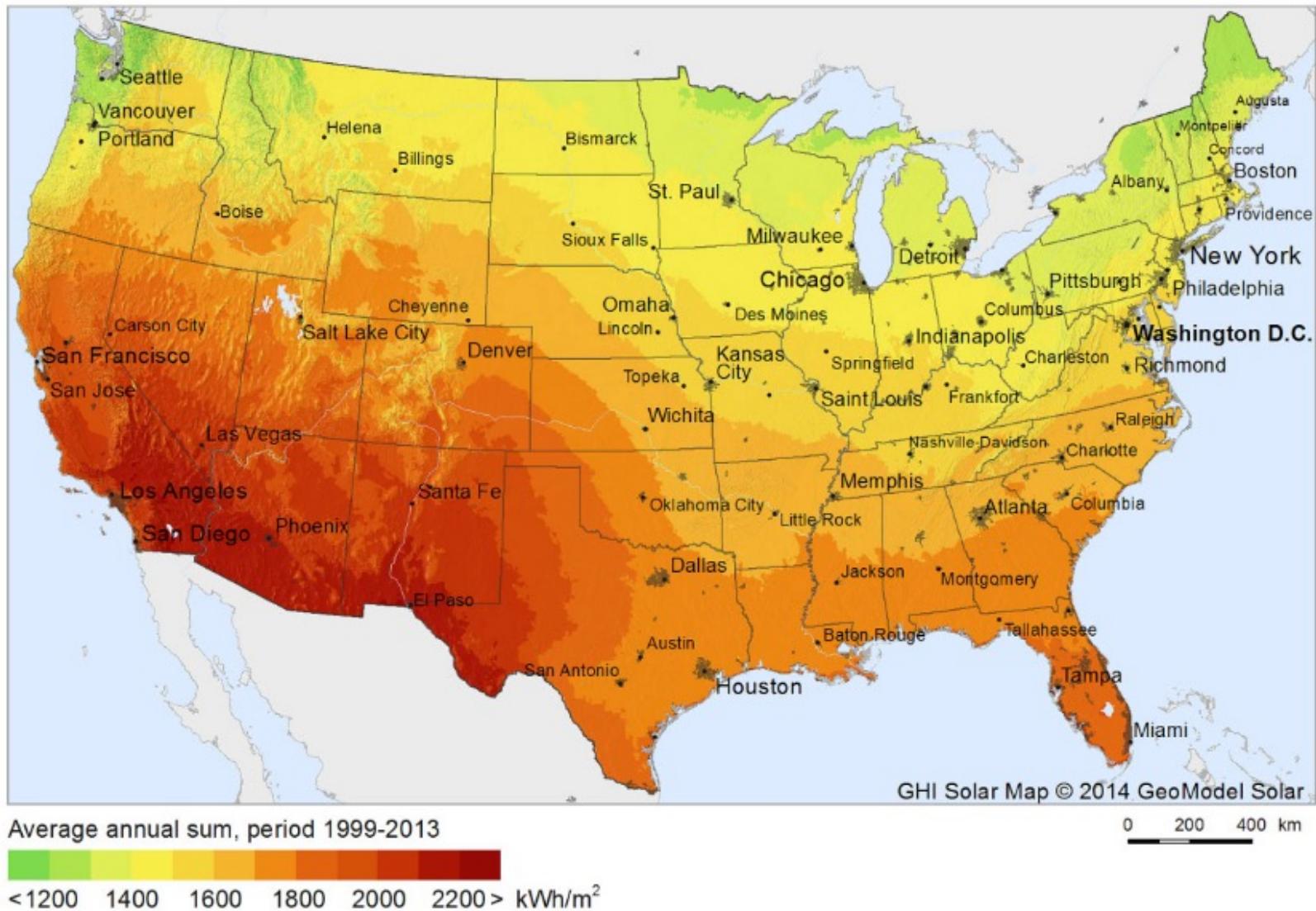
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Understanding Solar Cell Efficiency Limits

Consider the Source



Annual Solar Insolation: US

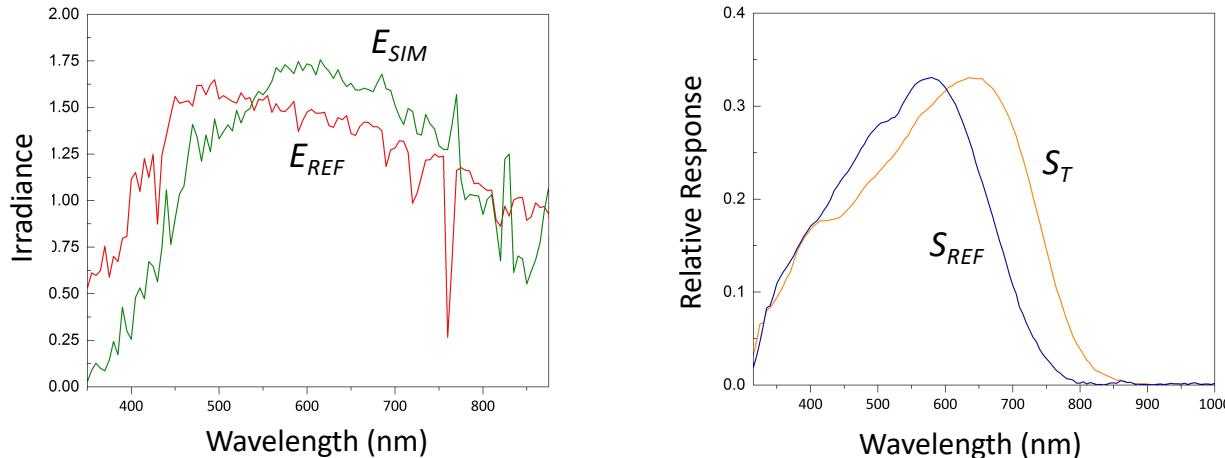


Measuring Single Junction Solar Cell Efficiency

Challenges:

- The laboratory spectrum (E_{REF}) is not identically equal to the reference solar spectrum (AM1.5G):
It is only simulated (E_{SIM})
- Reference detector spectral response (S_{REF}) not identical to the test solar cell (S_T)

Example spectra:



To correct for these differences we calculate the *spectral mismatch factor*

$$M = \frac{j_{SIM}^T j_{REF}^{REF}}{j_{REF}^T j_{SIM}^{REF}} = \frac{\int_{\lambda_1}^{\lambda_2} E_{SIM}(\lambda) S_T(\lambda) d\lambda}{\int_{\lambda_1}^{\lambda_2} E_{REF}(\lambda) S_T(\lambda) d\lambda} \cdot \frac{\int_{\lambda_1}^{\lambda_2} E_{REF}(\lambda) S_{REF}(\lambda) d\lambda}{\int_{\lambda_1}^{\lambda_2} E_{SIM}(\lambda) S_{REF}(\lambda) d\lambda}$$

$$M = 1 \text{ if } S_{REF} = S_T \text{ or } E_{REF} = E_T$$

$j_{SIM}^T = j_{SC}$ of test device using the simulated spectrum at 1 sun
 $j_{REF}^T = j_{SC}$ of test device using the reference AM1.5G spectrum at 1 sun
... etc.

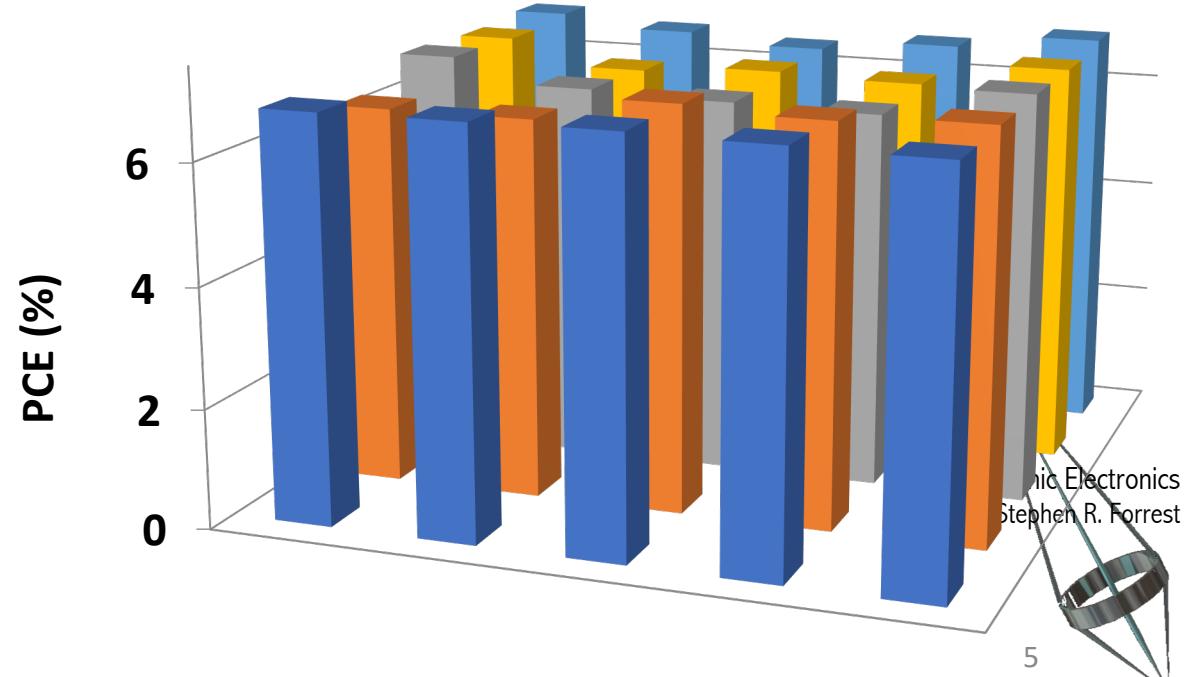
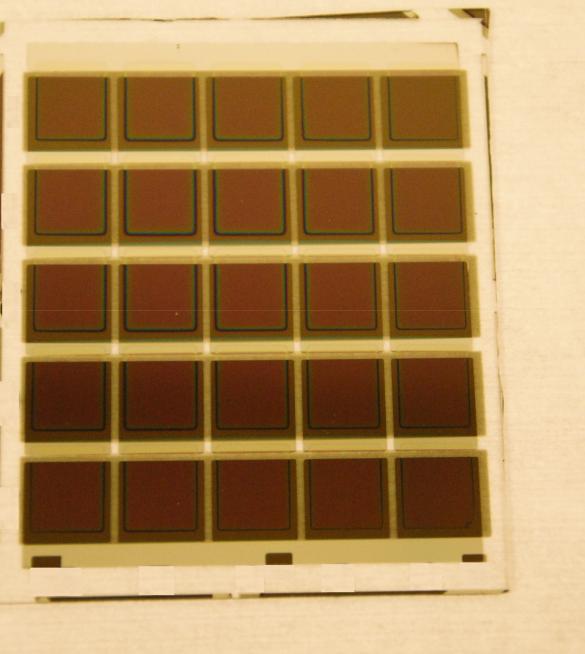
$$\text{Solar cell calibration is then: } j_{REF}^T = \frac{j_{REF}^{REF} \cdot j_{SIM}^T}{M \cdot j_{SIM}^{REF}}$$

For most accurate calibration: $M \approx 1$

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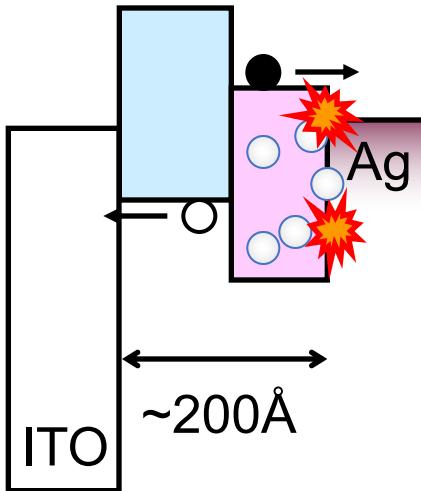
Organic Solar Cell Challenges

- High efficiency (>17%)
 - Large Module Size
 - High Reliability (>20 years)
 - Low Production Cost (<\$0.50/Watt)



Getting to High Efficiency: The Double Heterojunction

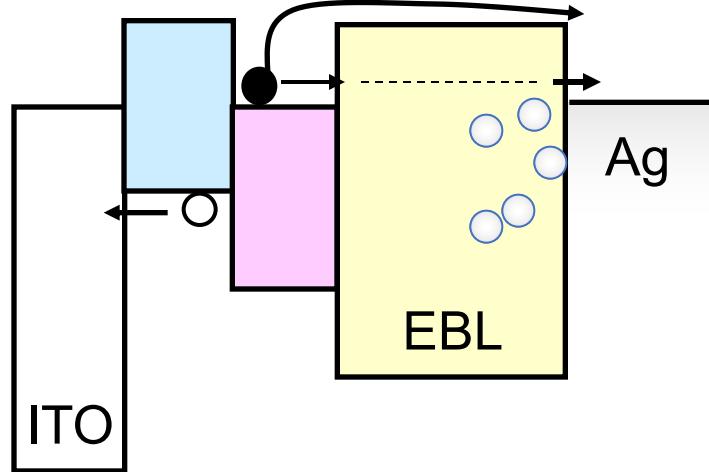
Problem



(Tang cell: 1%)

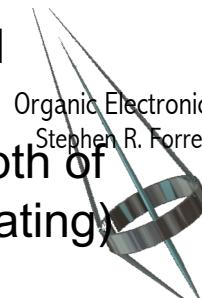
- cathode metal diffusion
- deposition damage
- exciton quenching
- vanishing optical field
- electrical shorts

Solution

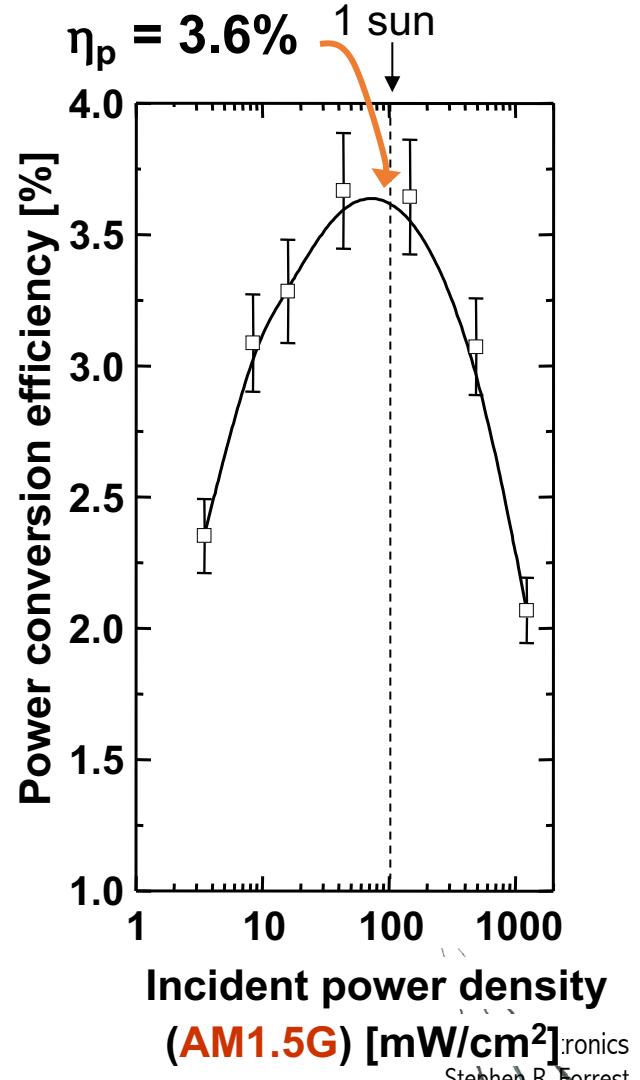
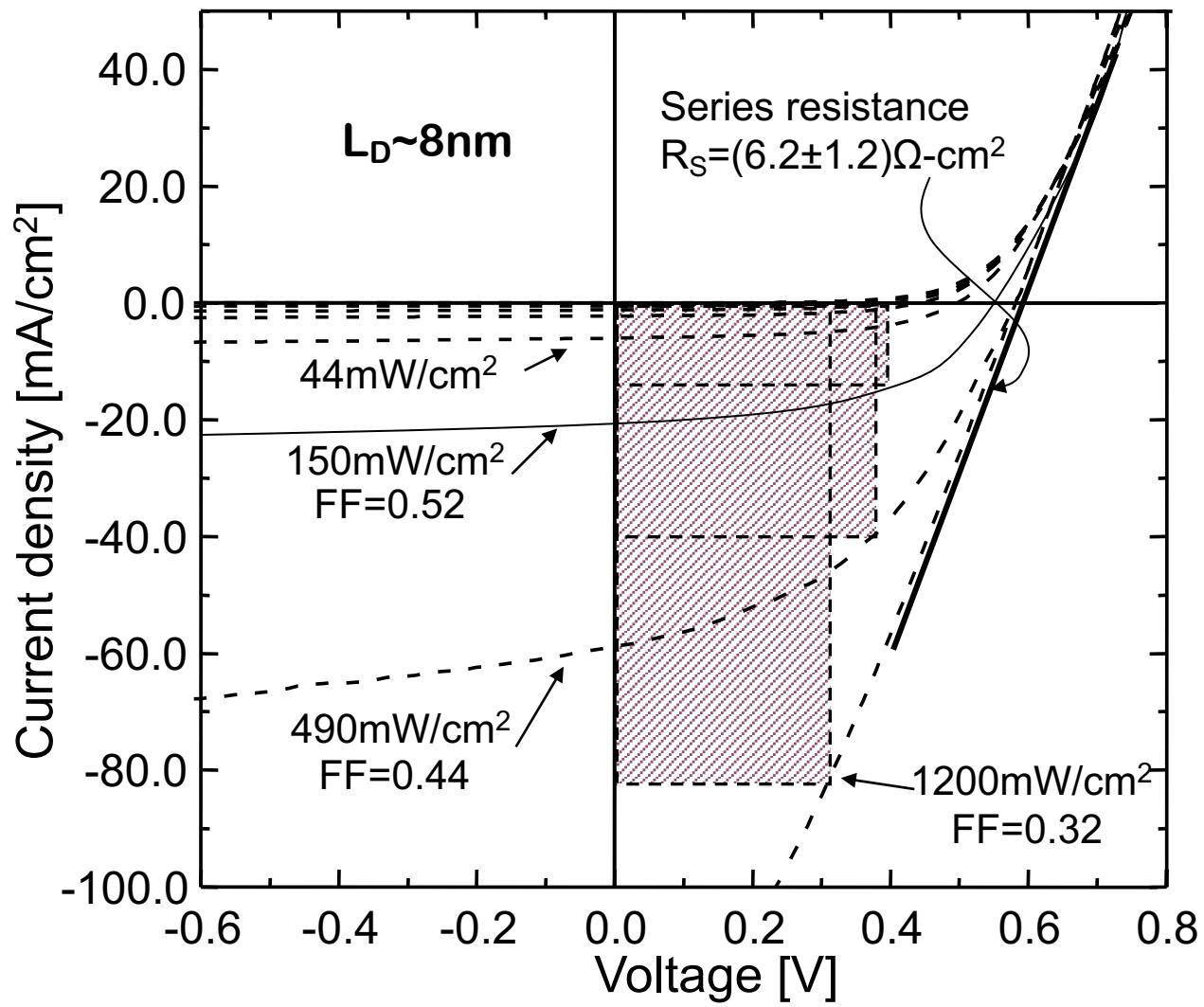


Introduce ‘Exciton Blocking Layer’ (EBL) to:

- confine excitons to active region
- separates active layer from metal
- act as a buffer to damage
- EBL thickness determined by depth of damage (if too thick, EBL is insulating)



High efficiency via increased exciton diffusion length: Introduction of fullerenes acceptors

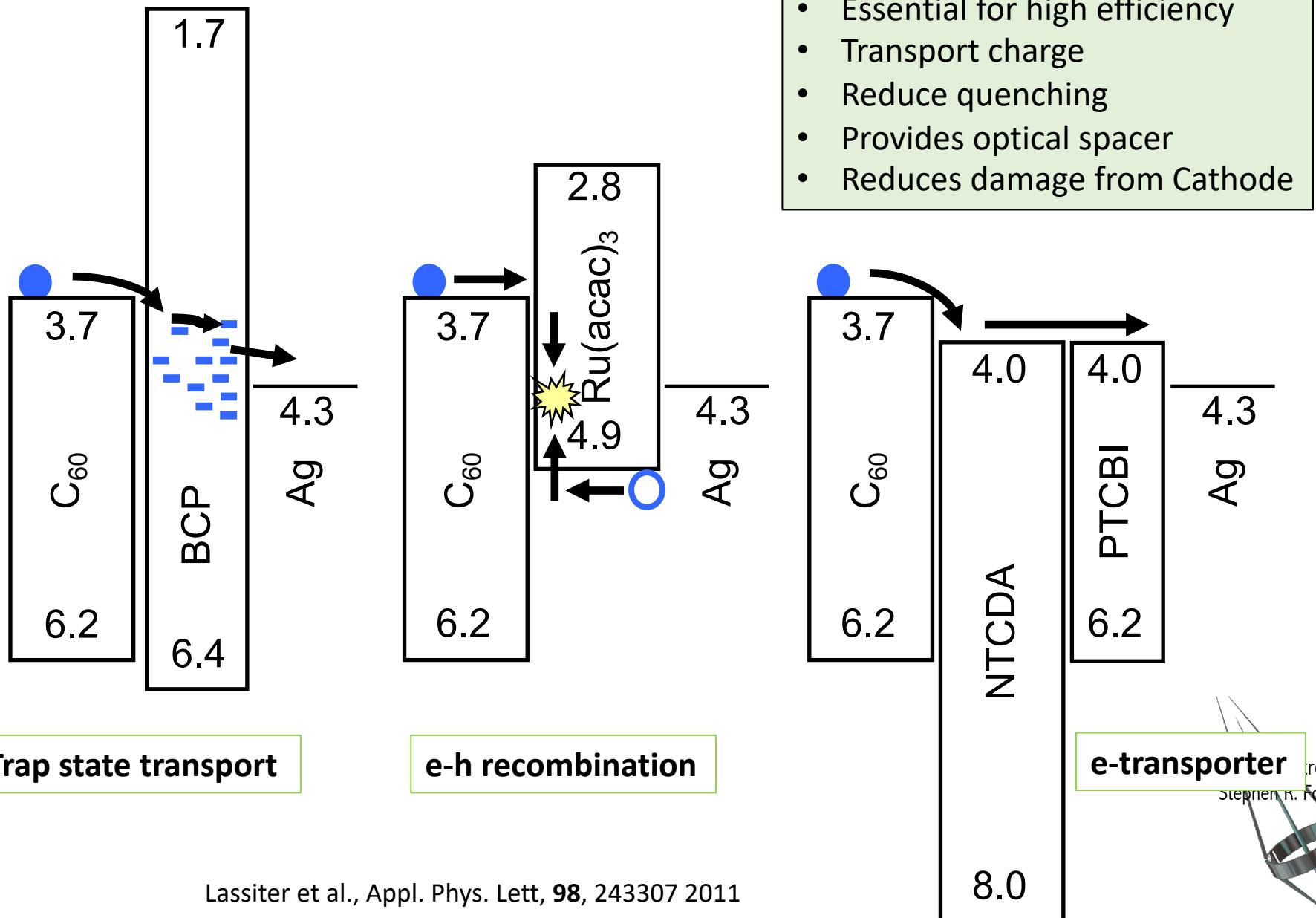


ITO/PEDOT/200Å CuPc/400Å C₆₀/150Å BCP/800Å Al

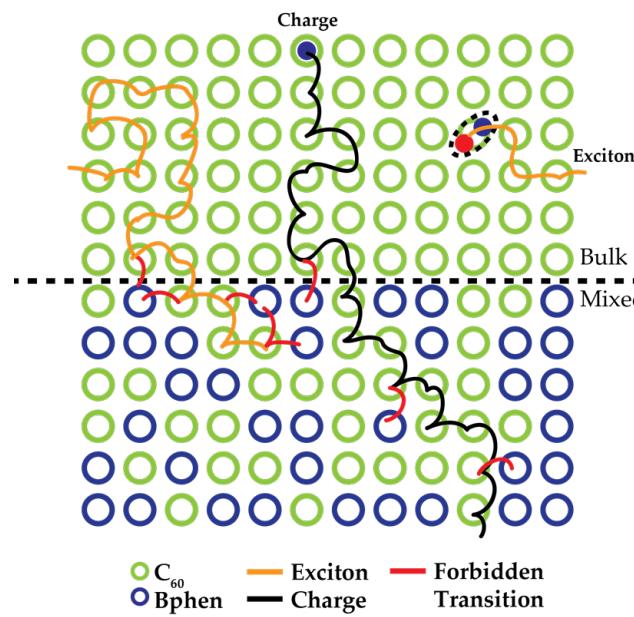
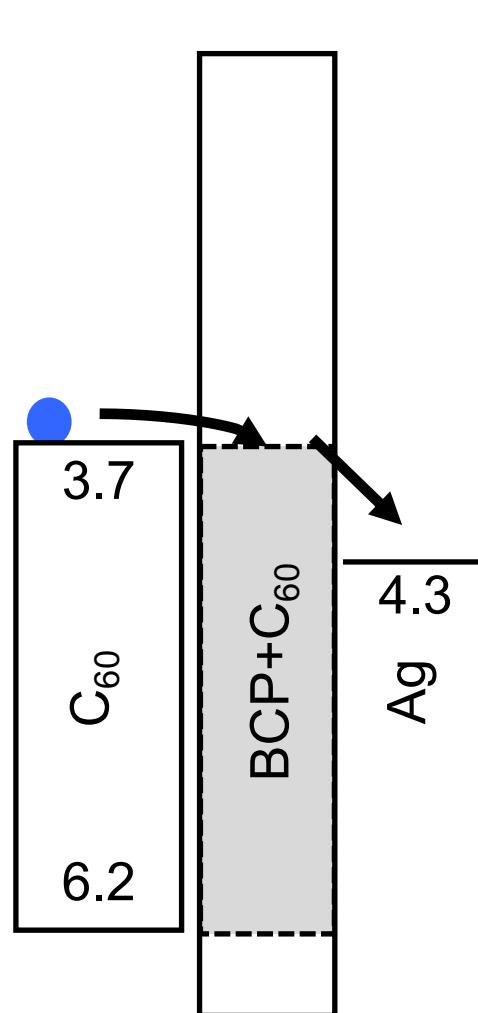
Peumans and Forrest., Appl. Phys. Lett., 79, 126 (2001)

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Species of Exciton Blockers



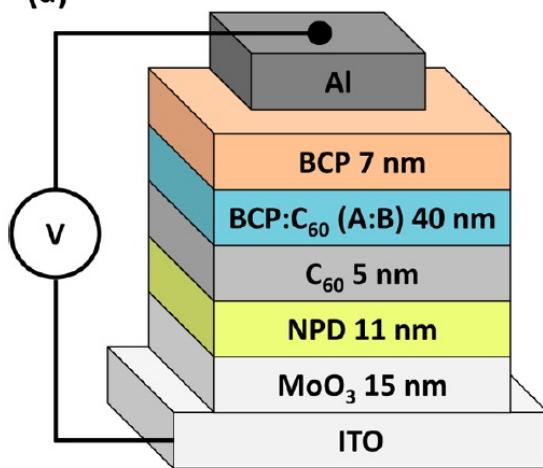
Electron Filtering Buffer Layer



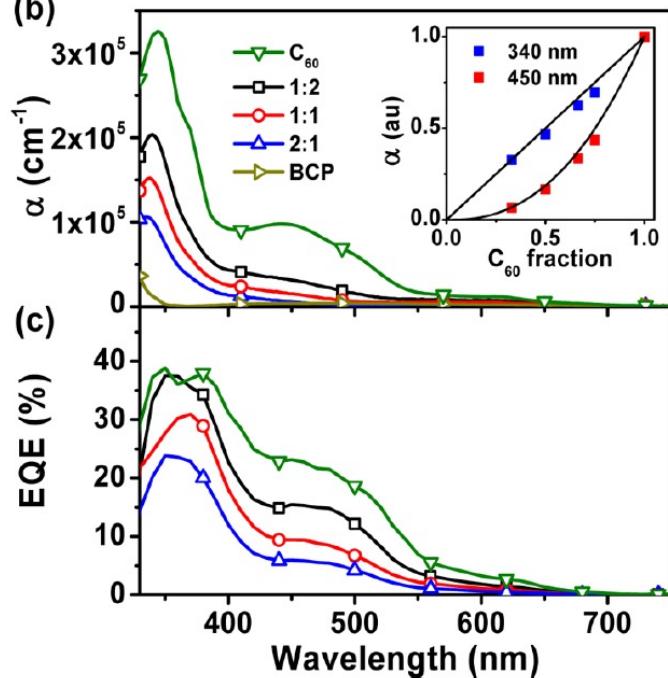
- Highly transparent
- Electron conductivity independent of C₆₀ conc. to ~30%
- Compound buffer: C₆₀:Bphen/BPhen
- Active region: DBP:C₇₀

C_{60} :Bphen Electron Filtering Blockers

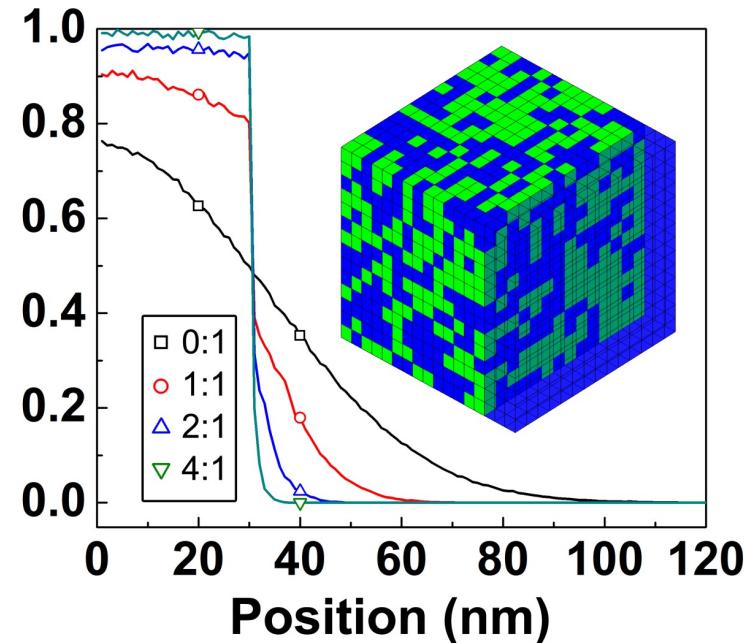
(a)



(b)

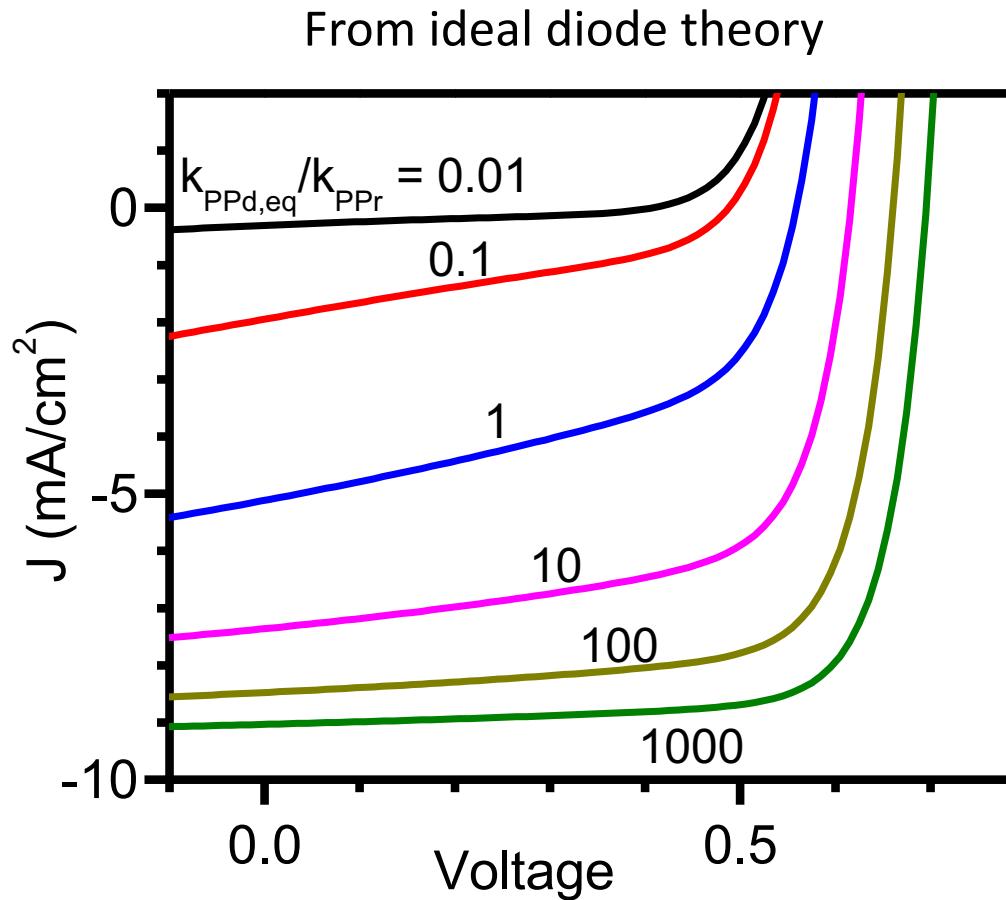


Exciton Population

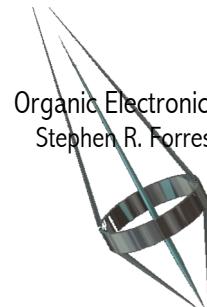


Doping (C_{60} :BCP)	Blocking Efficiency (%)
1:0	49.9 ± 0.8
1:1	81.0 ± 0.6
1:2	94.9 ± 0.6
1:4	98.4 ± 0.6

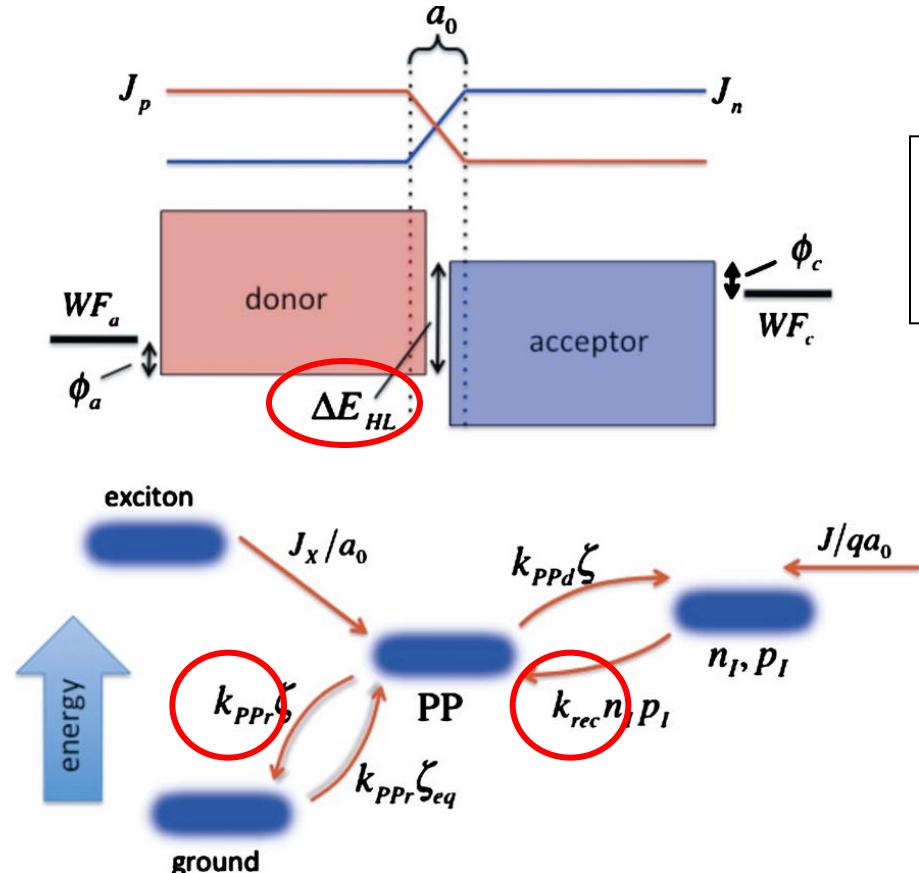
The central importance of morphology



- PP recombination \Rightarrow Reverse Slope
- Best morphologies limit k_{PPr} at interface:
 - **Steric hindrance**
 - **Disorder at interfaces/order in the bulk**



Open-circuit voltage in OPVs

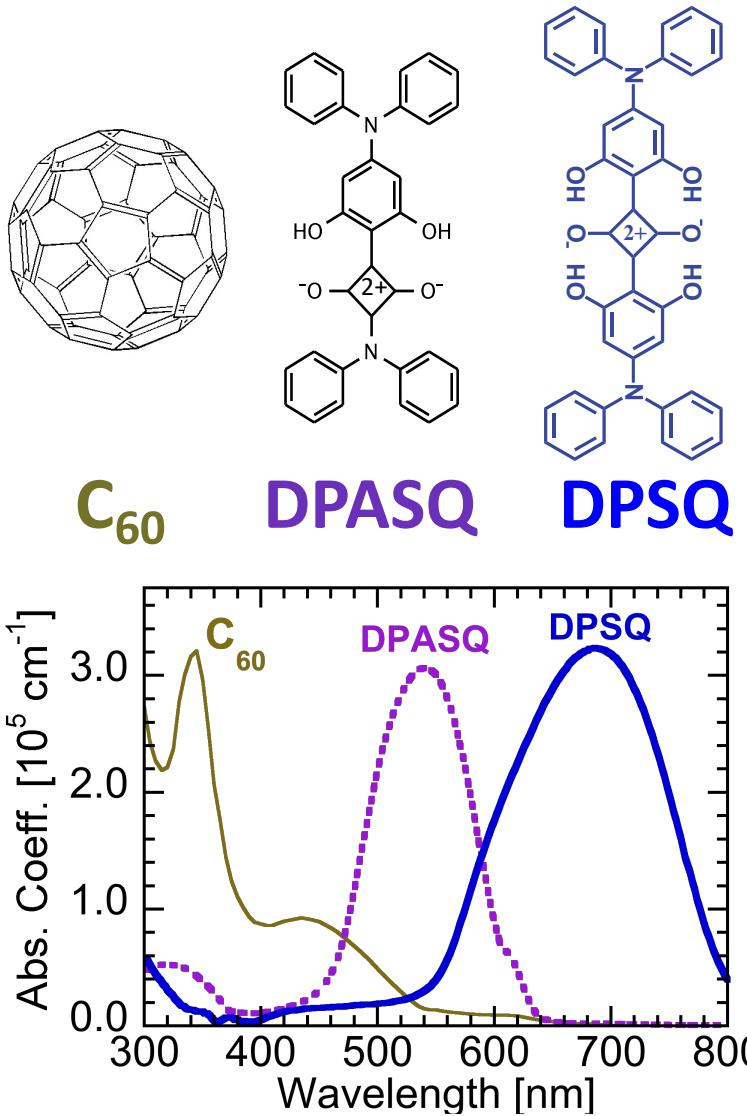


$$qV_{OC} = \Delta E_{HL} - nk_B T \ln \left[\frac{k_{PPr}}{k_{PPd}} \frac{k_{rec} N_L N_H}{J_X / \alpha_0} \right].^*$$

- Material choice determines:
 - ΔE_{HL} (HOMO-LUMO Gap)
 - Steric hindrance (MO overlap)
- Device processing/morphology can limit V_{OC} losses:
 - k_{rec} (PP formation)
 - k_{PPr} (PP recombination)

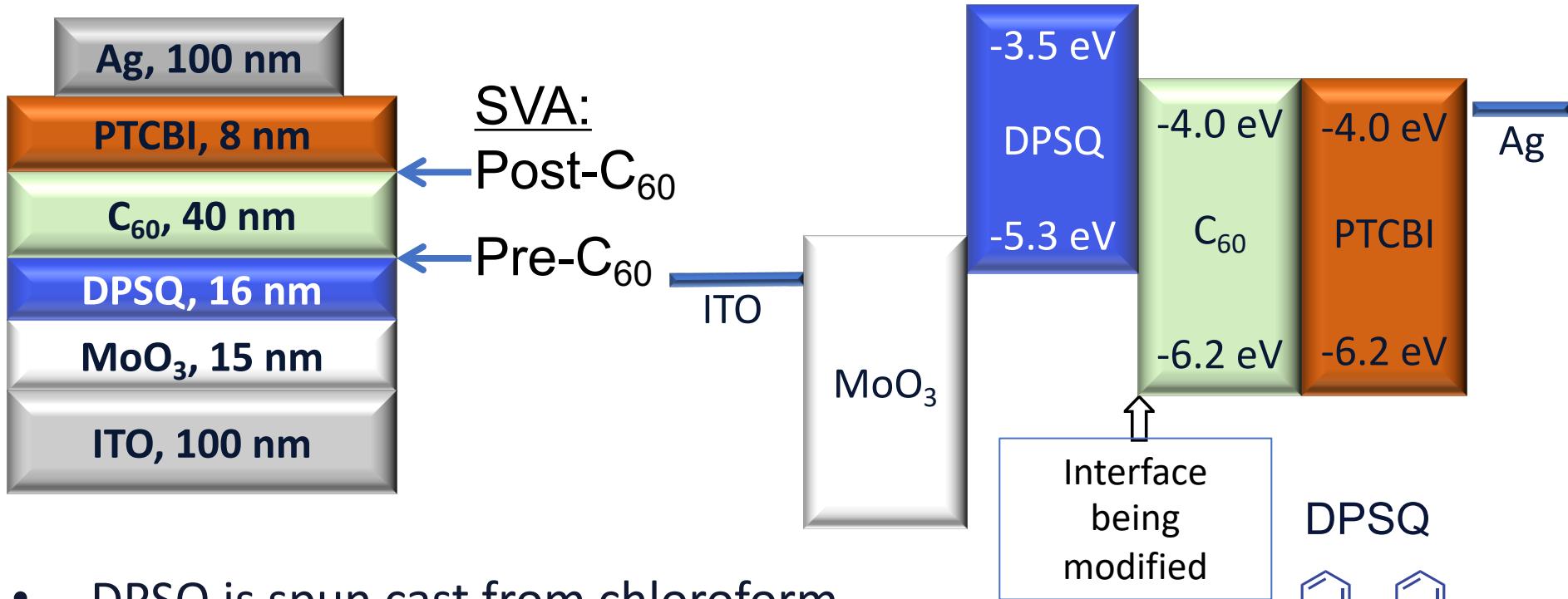
Squaraine/Fullerene Solar Cells

Controlling k_{ppd} via morphology

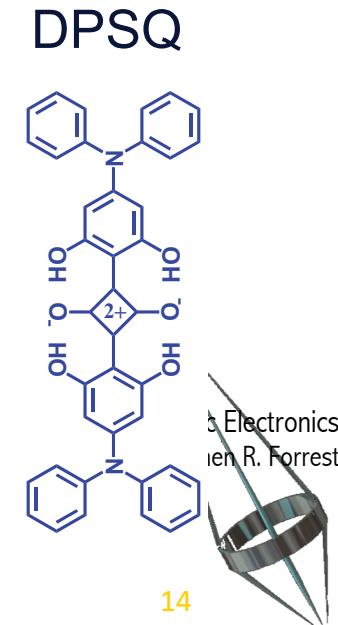


- Squaraines:
 - Very large absorption coefficient.
 - Favorable HOMO/LUMO energies.
 - Large V_{OC} .
 - Excellent transport.
 - Simple synthesis.
 - Must be solution processed.
- Bilayer devices:
 - Simplicity allows study of fundamental processes.

DPSQ Device Structure

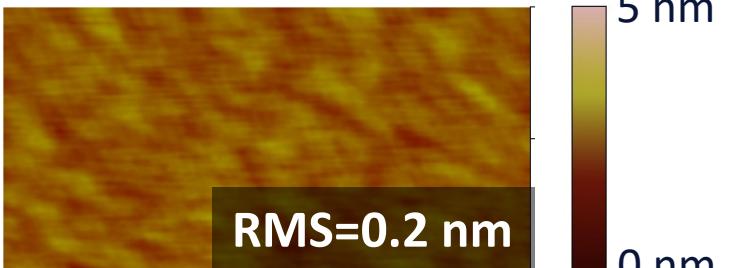


- DPSQ is spun cast from chloroform.
- Other layers deposited by thermal evaporation.
- **Solvent vapor annealing (SVA):**
 - 10 min exposure to a saturated dichloromethane vapor for to “anneal” squaraine component.



SVA Pre- C_{60}

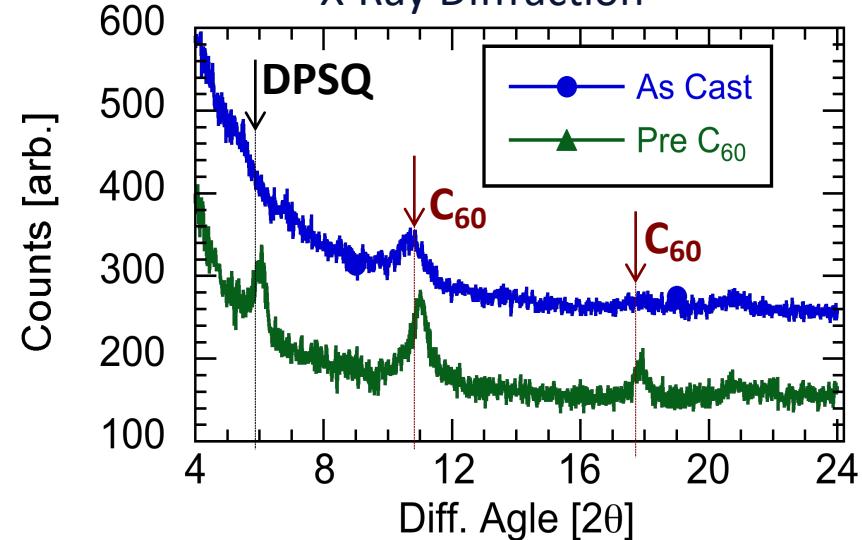
As Cast DPSQ



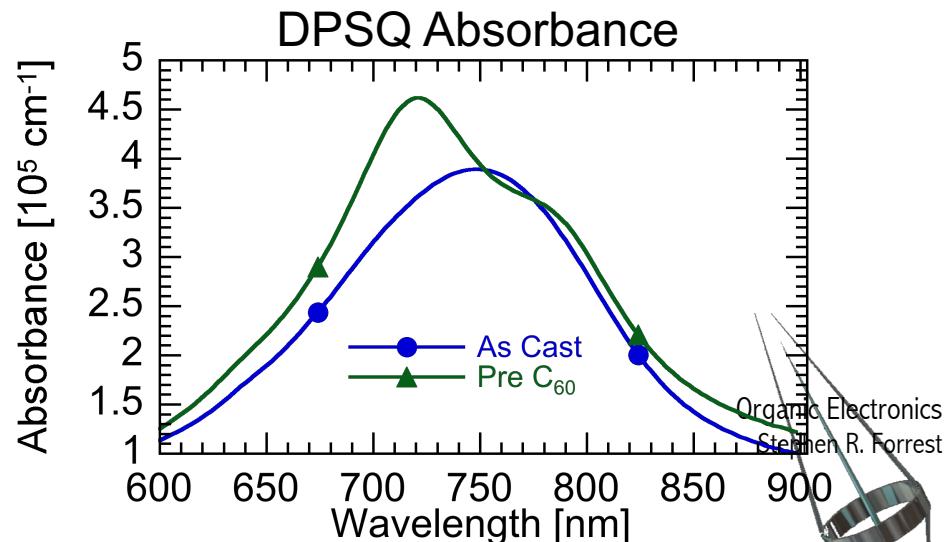
DPSQ SVA pre- C_{60}



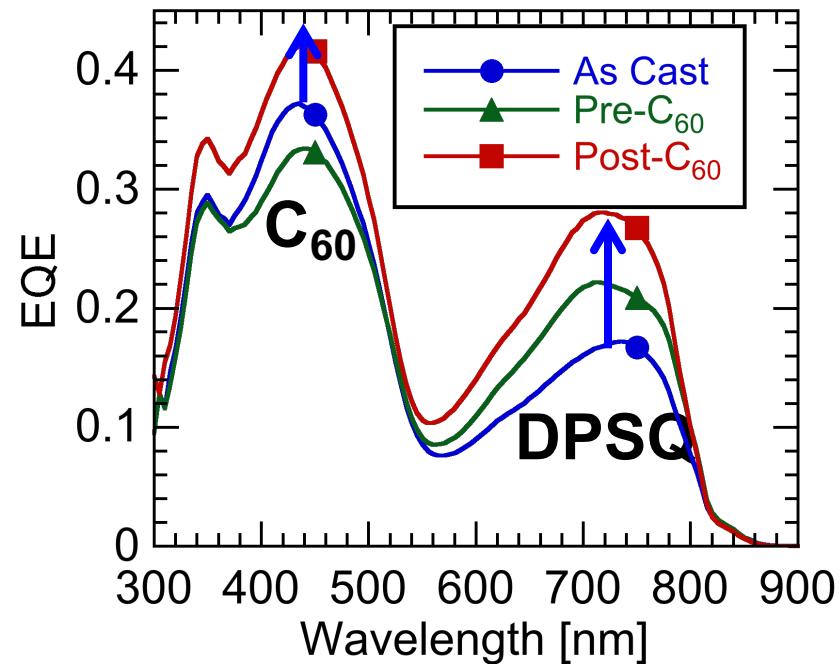
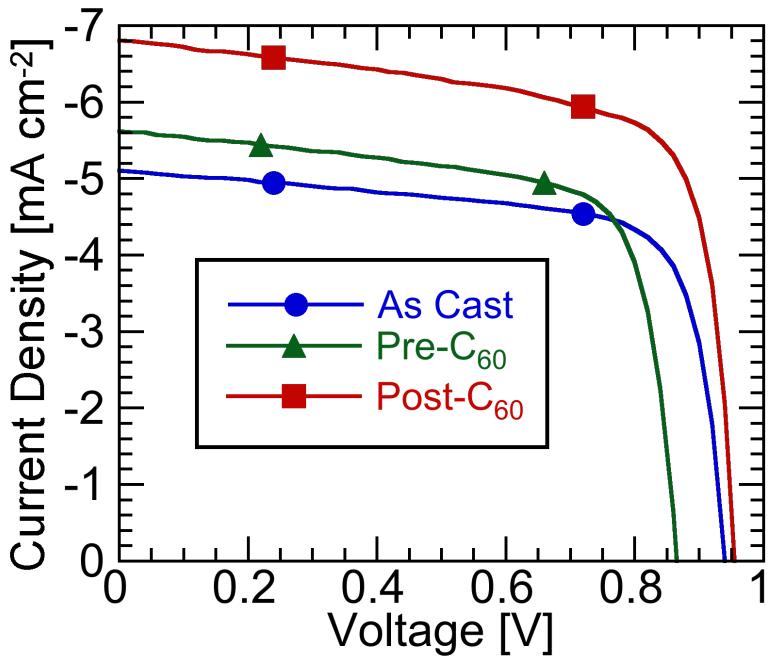
X-Ray Diffraction



- SVA Pre C_{60} :
 - Crystallizes and roughens DPSQ.
 - Crystalline DPSQ templates *quasi-epitaxial* C_{60} growth.



Devices SVA Post-C₆₀



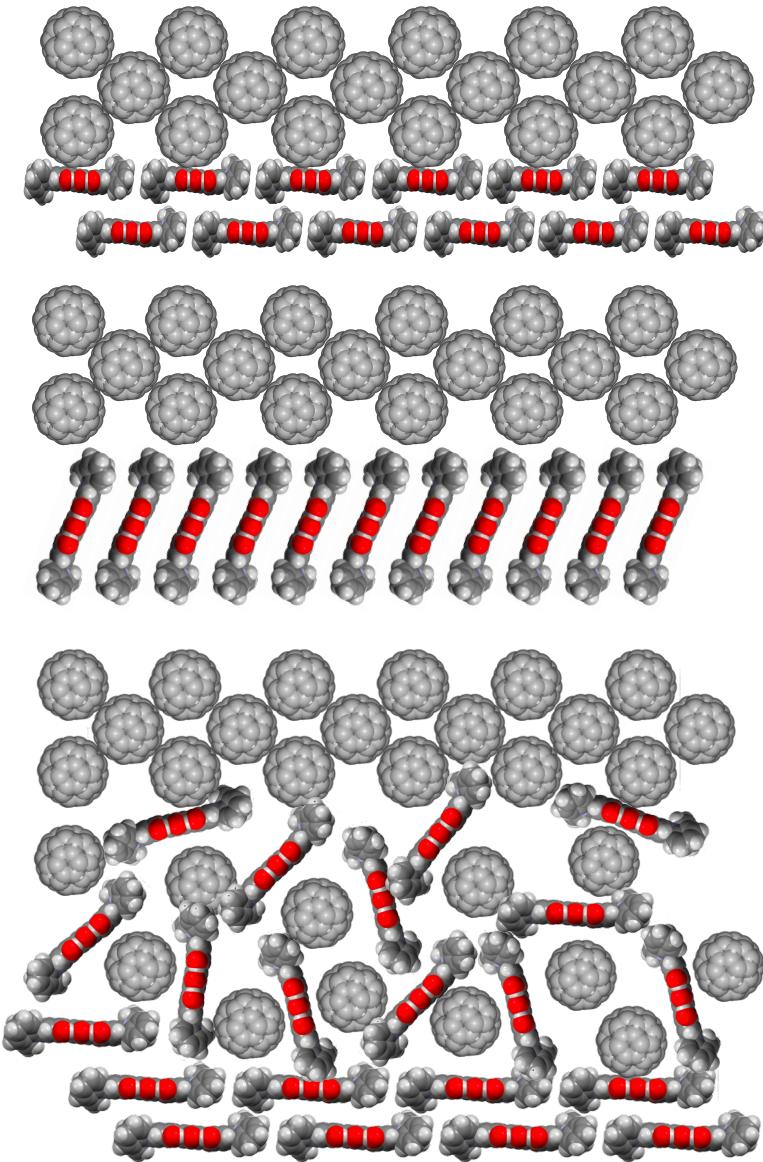
- SVA post-C₆₀
 - DPSQ EQE \uparrow 80%.
 - J_{SC} \uparrow 25%.
- No loss in V_{OC}
 - k_{PPr} unchanged.

Process	J _{SC} [mA cm ⁻²]	V _{OC} [V]	FF [%]	η _P [%]
As Cast	5.3±0.3	0.94	73	3.6±0.2
Pre-C ₆₀	5.6±0.3	0.86	70	3.4±0.2
Post-C ₆₀	7.0±0.4	0.96	71	4.8±0.3

Achieving the Ideal Morphology

C_{60}			
	As Cast	Pre C_{60}	Post C_{60}
Bulk DPSQ	Amorphous	Ordered	Mod. Order
Bulk C_{60}	Weak order	Ordered	Weak Order
Interface	Disordered	Ordered	Disordered
Surface	Smooth	Rough	Smooth
k_{PPr}	Low	High	Low
V_{OC}	High	Low	High
J_{SC}	Low	Moderate	High

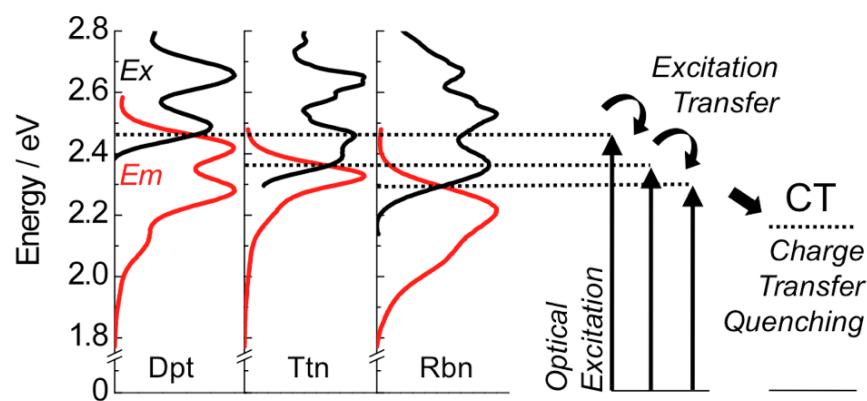
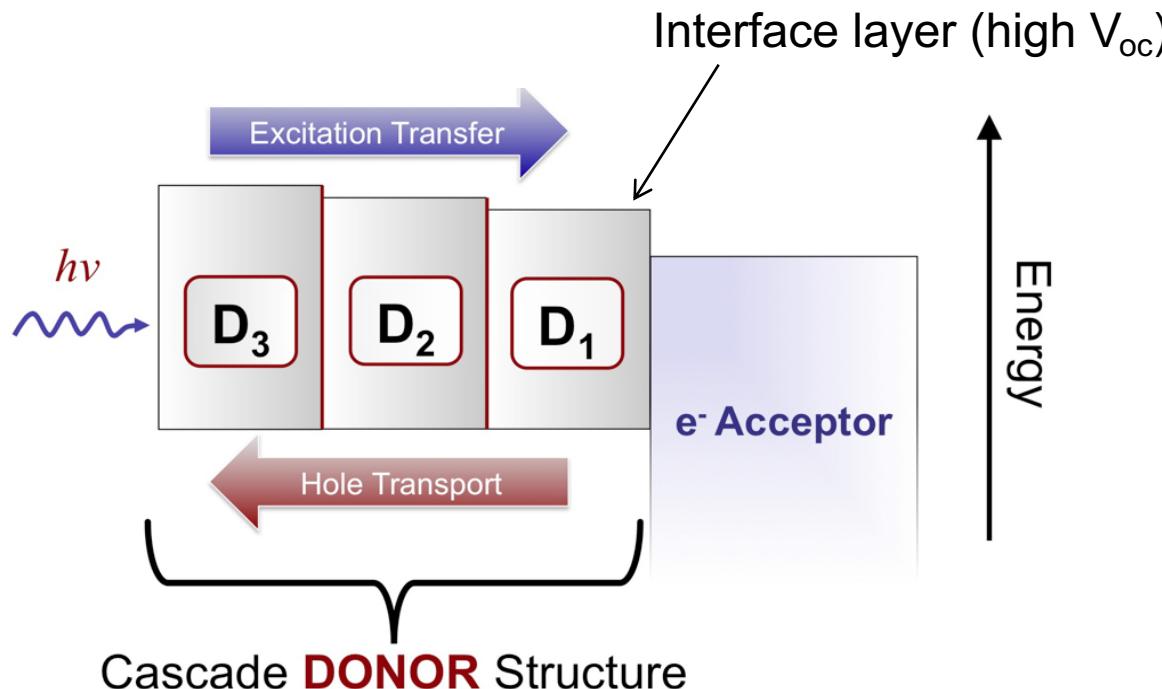
Morphology vs. V_{OC}



$$qV_{OC} = \Delta E_{HL} - nk_B T \ln \left[\frac{k_{PPr}}{k_{PPd}} \frac{k_{rec} N_L N_H}{J_X / \alpha_0} \right]$$
$$k_{rec} = \gamma = \frac{q}{\varepsilon} (\mu_e + \mu_h)$$

- Worst case scenario: perfectly ordered crystalline interface and bulk, Face-on .
 - High k_{PPr} and k_{rec}
- Better Scenario I: Perfectly crystalline and end-on orientation
- Even Better Scenario II: crystalline bulk, intermixed interface
 - Poor coupling between like-molecules (C₆₀-C₆₀ and SQ-SQ) reduces PP formation (k_{rec}) probability.
 - Overcomes enhanced k_{PPr} due to facial contact

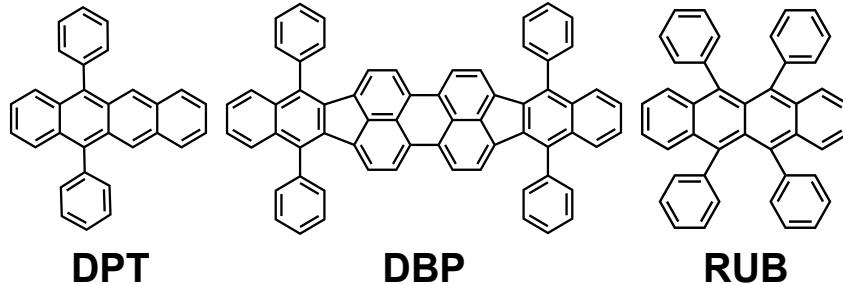
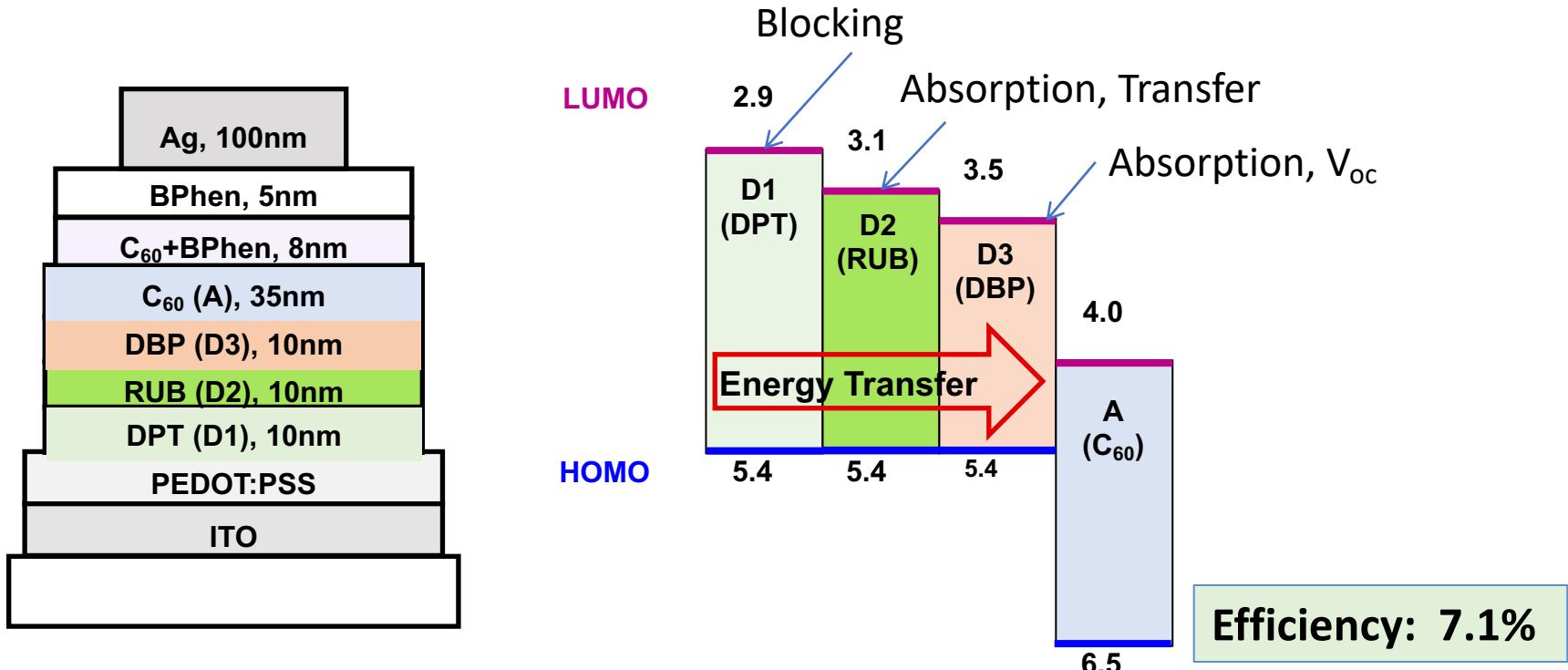
Increasing solar coverage: Exciton Cascades



Schlenker, et al., *Chem. Mater.*, **23**, 4132 (2011).

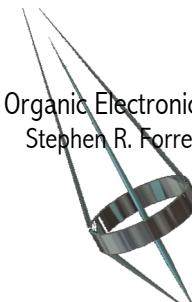


High Efficiency Donor Cascade Device

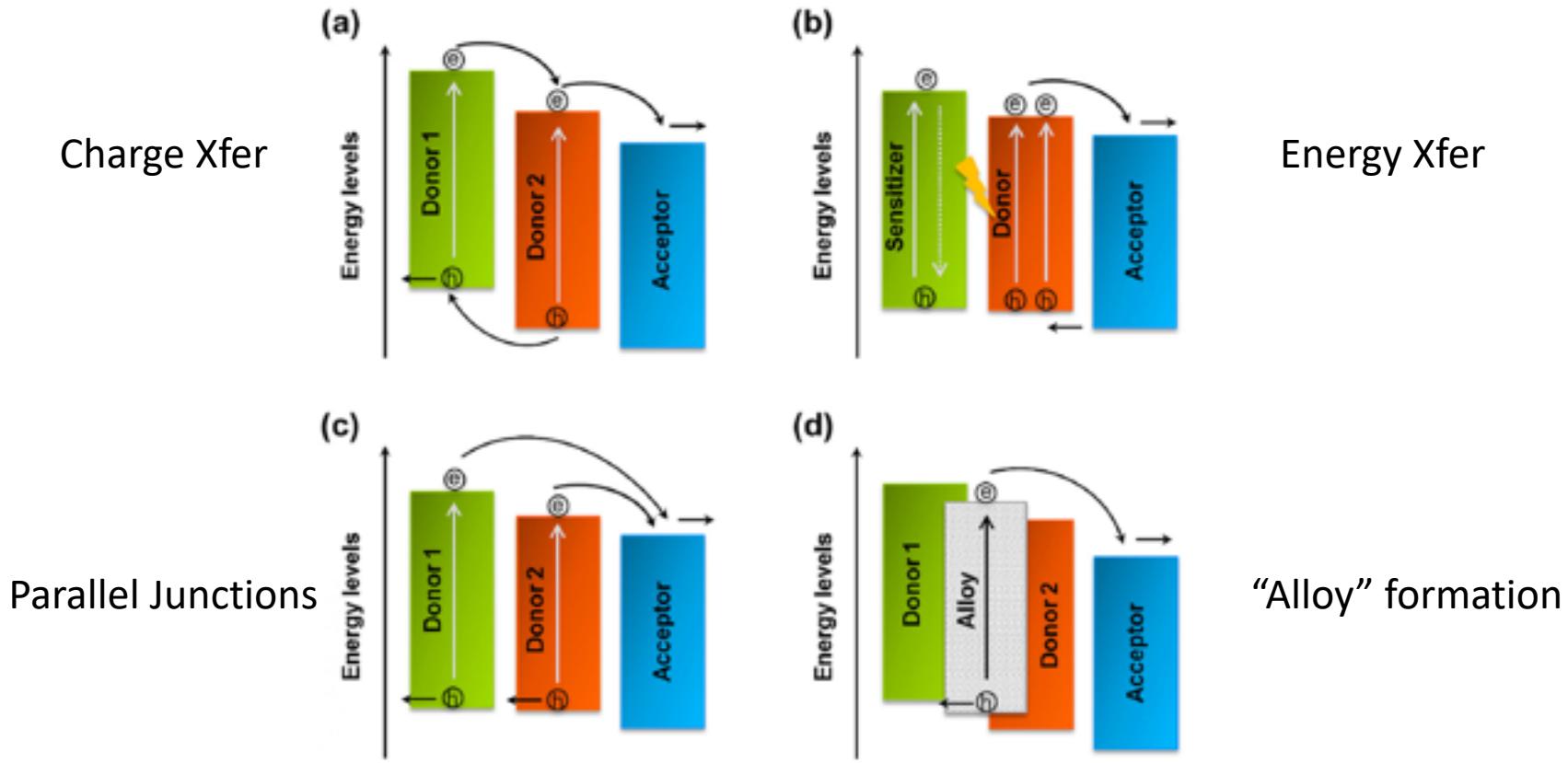


O. L. Griffith & S. R. Forrest, *Nano Letters*, 14, 2353 (2014).

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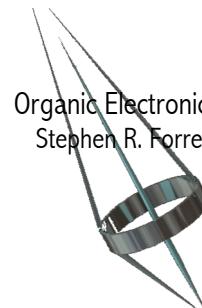


Ternary BHJs Increase Solar Coverage

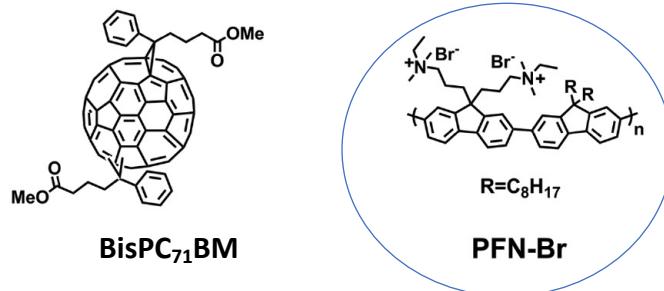
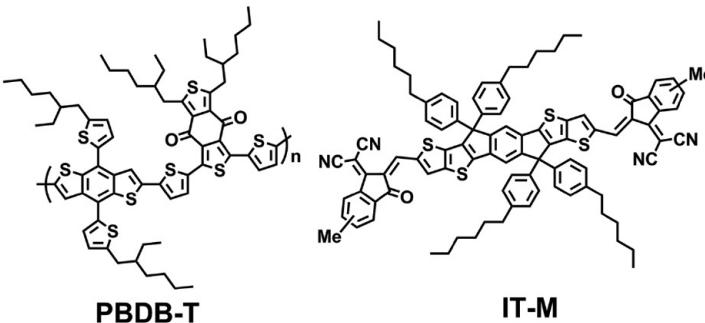


Features of ternary blends:

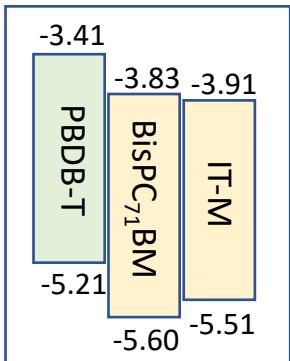
- V_{OC} of the ternary lies between the extremes of the two subcell junctions
- Materials chosen to cover solar spectrum
- Can be DA₁A₂ or AD₁D₂ junctions
- Morphology is key
- Probably more than one process governs performance
- Molecular alloy formation unlikely



Example DA₁A₂ ternary BHJ



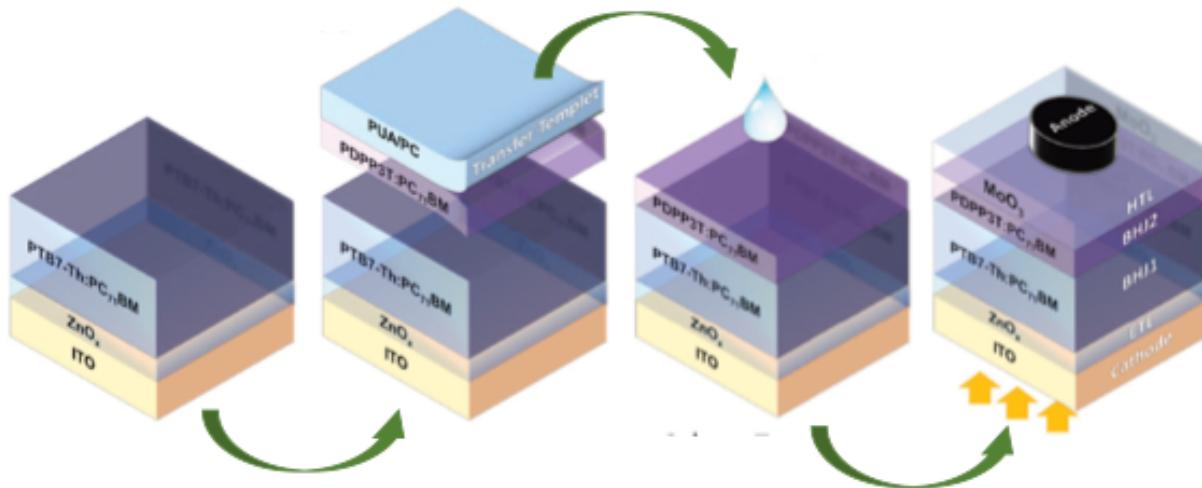
Exciton blocker



D:A ₁ :A ₂ ratio	V_{OC} (V)	$j_{SC}^{(a)}$ (mA/cm ²)	FF)	η_P (max) (%)	η_P (ave) ^(b) (%)
1:1:0	0.937	16.7	0.69	10.80	10.45
1:1:0.2	0.952	17.4	0.74	12.20	11.75
1:0:1	1.02	10.6	0.58	6.25	5.86

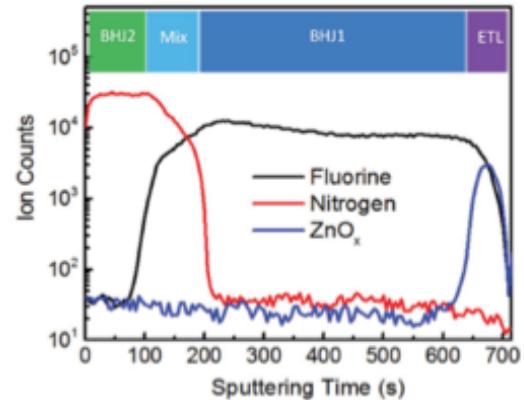
- Cell area = 4 mm².
- Sample size = 100 diodes

Bi-tertiary OPV

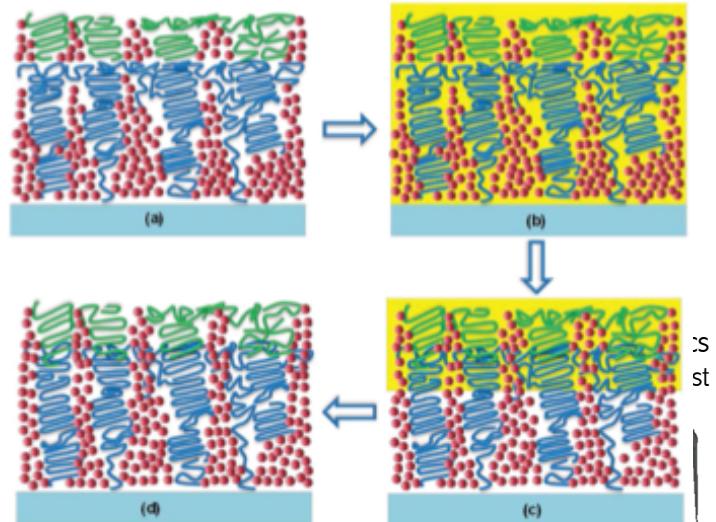


Intermixing of two donors creates continuous hole and electron conduction

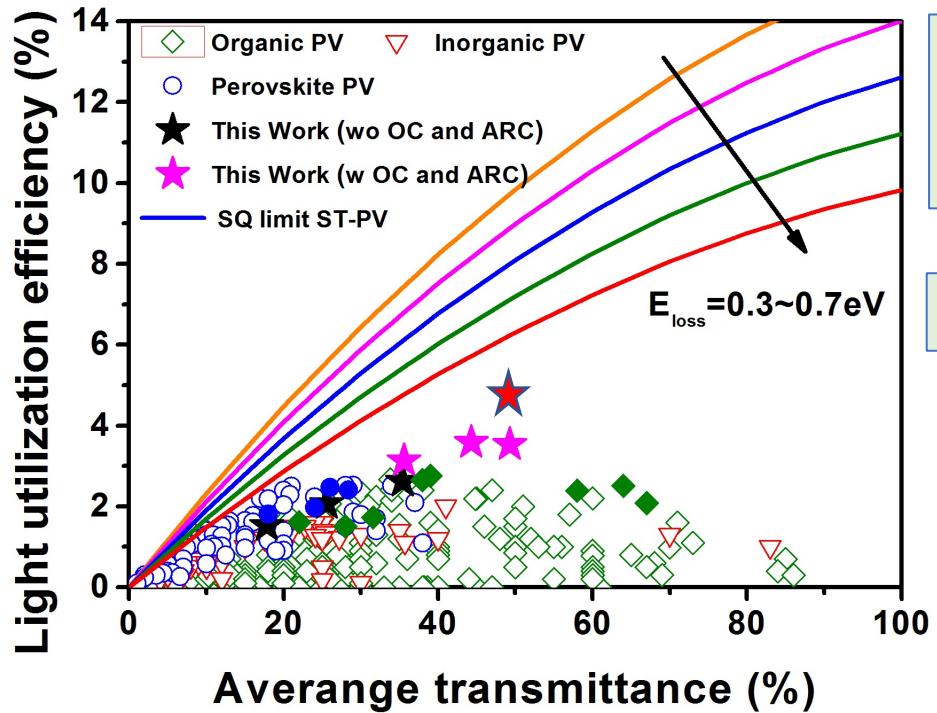
Cell ^(a)	V_{OC} (V)	$j_{SC}^{(b)}$ (mA/cm ²)	FF	η_P (max) (%)	η_P (ave) ^(c) (%)
BHJ1	0.81	18.5	0.70	10.5	10.3
BHJ2	0.69	7.4	0.71	3.6	3.5
BHJ1/2	0.77	23.8	0.67	12.3	11.9



(b)



Wavelength-selective Absorption Can Lead to Semitransparent OPVs



Power generating windows (transparent in the visible, absorbing in the NIR) are a major opportunity unique to OPVs

Transparent OPV Figure of Merit

$$LUE = PCE \times APT$$

LUE: light utilization efficiency

PCE: power conversion efficiency

APT: average photopic transmission

$$APT = \frac{\int T(\lambda)P(\lambda)S(\lambda)d(\lambda)}{\int P(\lambda)S(\lambda) d(\lambda)}$$

λ : wavelength;

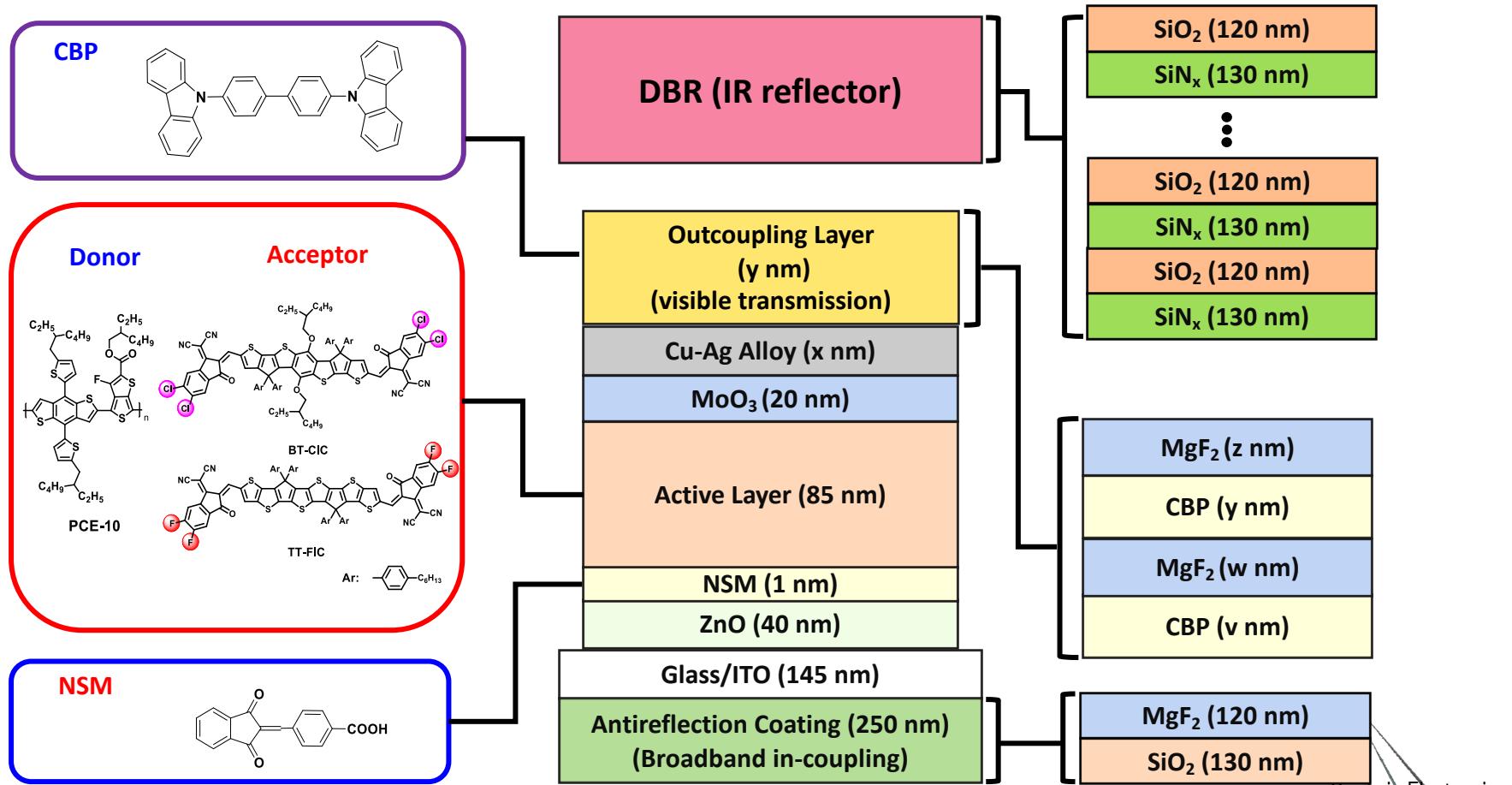
T : transmission

P : photopic response; S : solar photon flux (AM1.5G)

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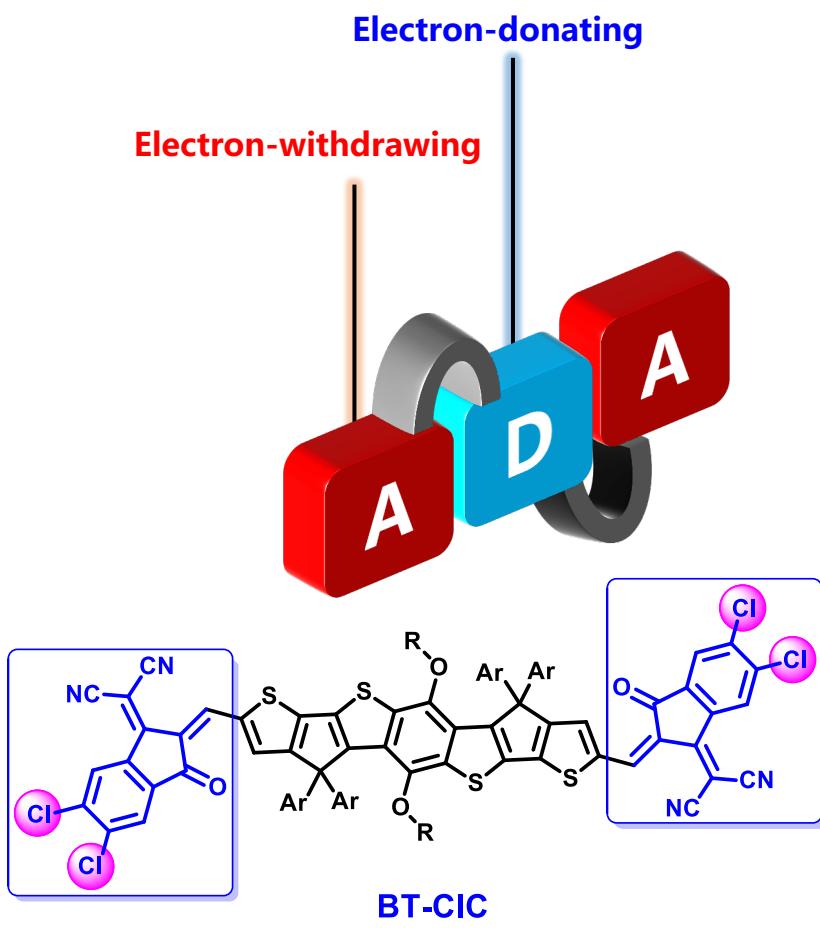
Semi-Transparent Device Materials & Structures

Example of Photon Management

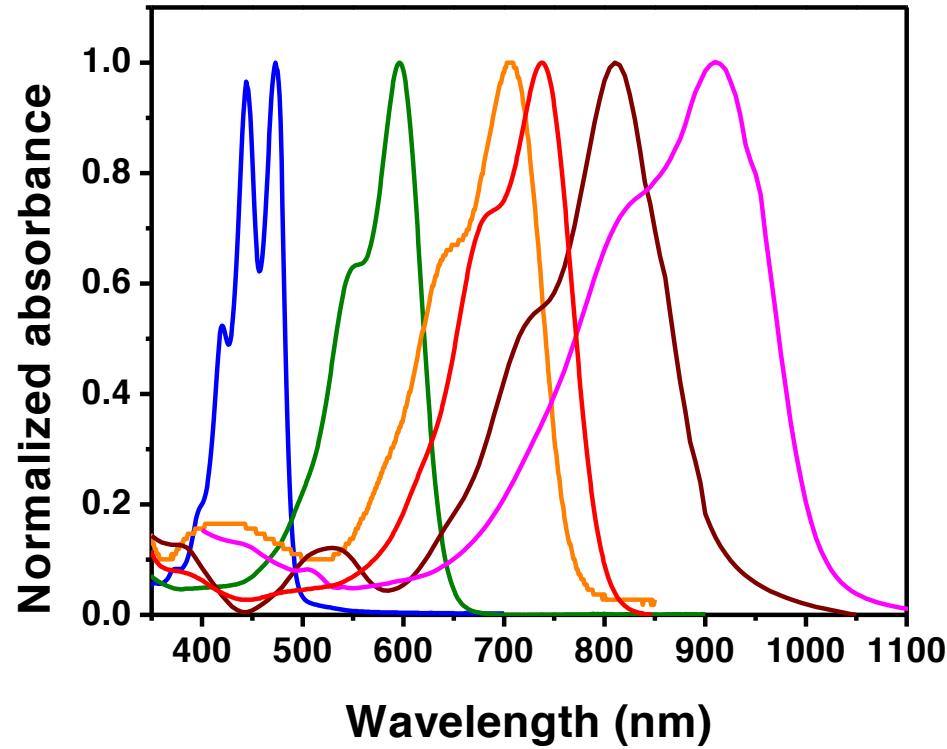


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Non-Fullerene Acceptor Molecular Design

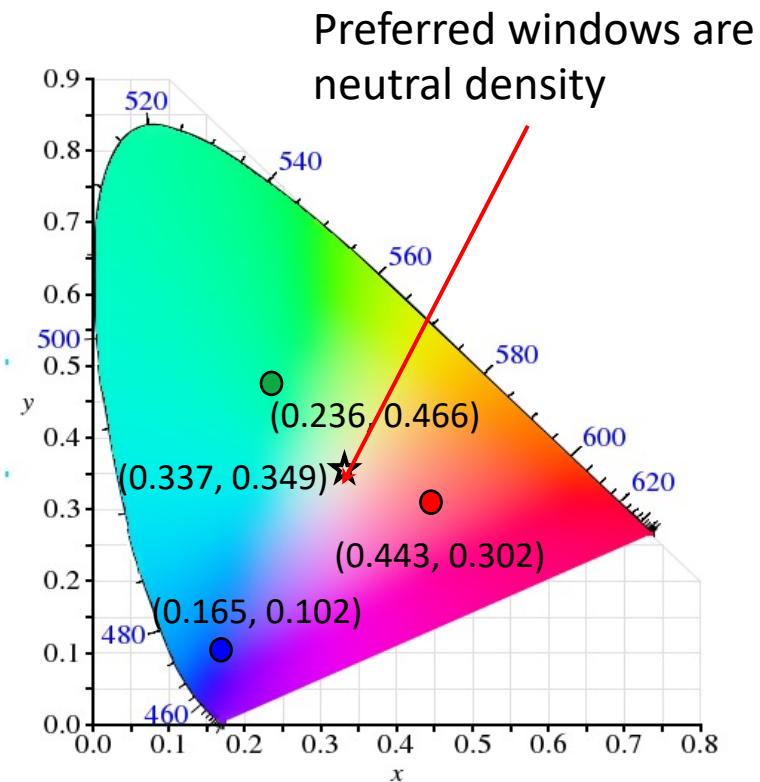


Absorption tunability presents opportunities unique to OPVs



Semi-Transparent Organic Solar Cells

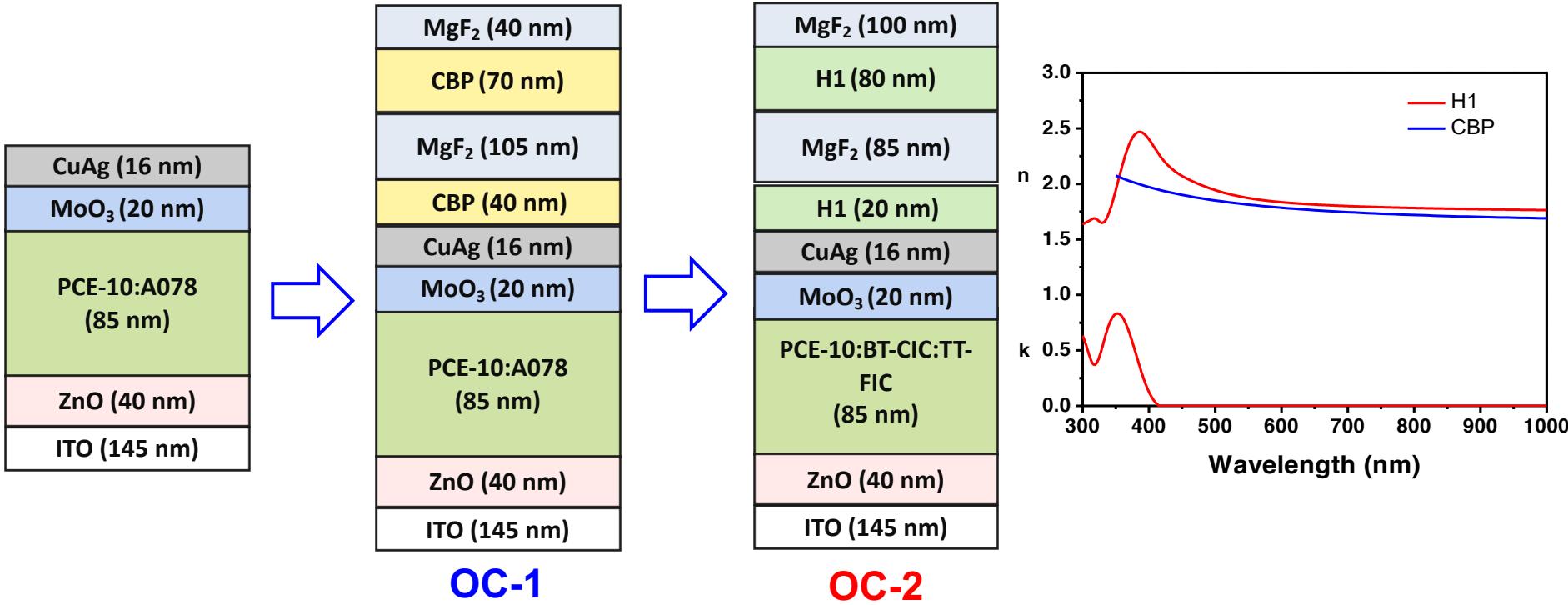
Color Tunable Windows



Active Layer	J_{sc} [mA/cm ²]	V_{oc} [V]	FF [%]	PCE [%]
PCE-10:BT-CIC (1:1.5)	22.5 (21.3)	0.70	71.0	11.2
PCE-10:DTD-FIC (1:1.5)	25.6 (21.3)	0.64	69.5	11.3

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Optical Outcoupling Layers



Device	J_{sc} [mA/cm ²]	V_{oc} [V]	FF	PCE [%]	APT [%]	LUE [%]
WO OC	18.4	0.72	0.62	8.3	30.2	2.51
W OC-1	18.1	0.74	0.65	8.7	48.3	4.20
W-OC-2	-	-	-	-	51.2	5.2

